



# RELIABILITY MONITOR SUMMARY

QUARTERLY SUMMARY, QUARTER 4, 1995

January 15, 1996

PERFORMED PER THE REQUIREMENTS OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION.

ORIGINATOR:

\_\_\_\_\_  
MUOI VU  
QUALITY ENGINEER

\_\_\_\_\_  
DATE

APPROVED:

\_\_\_\_\_  
TOM HOYLE  
SENIOR RELIABILITY ENGINEER

\_\_\_\_\_  
DATE



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## STANDARD STRESS TEST DESCRIPTIONS

Test	Description
HTOL	High Temp Op Life, 150°C, 5.75V
HTOL2	High Temp Op Life, 125°C, 5.75V
HTSSL	High Temp Steady State Life, 150°C, 5.75V
HTSSL2	High Temp Steady State Life, 125°C, 5.75V
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100% RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C, 85% RH, 5.5V Bias
85/85	Hi-Accel Saturation Test, 85°C, 85V
TC	Temp Cycle, 125°C to -40°C
TC2	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 165°C, No Bias



## WAFER FAB AREAS

FAB #	LOCATION
CA	SAN JOSE, CALIFORNIA
TX	ROUND ROCK, TEXAS
MN	BLOOMINGTON, MINNESOTA
FR	MHS, FRANCE

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## ASSEMBLY LOCATIONS

COMPANY/LOCATION	ID
Anam-Buchon/Korea	KOREA-A
Asat/Hongkong	ASAT-B
Cypress/USA	USA-C
Dynesem/Phillipine	PHIL-D
Cypress-Minesota/USA	USA-E
Astra/Indonesia	INDNS-F
Golden Altos/USA	USA-G
Hyundai/Korea	KOREA-H
Indy/USA	USA-I
Kyocera/Japan	JAPAN-K
Anam-Seoul/Korea	KOREA-L
Anam/Phillipine	PHIL-M
Omedata/Indonesia	INDNS-O
Pantronix/USA	USA-P
Anam-Bupyong/Korea	KOREA-Q
TSCM/Taiwan	TAIWAN-R
Chinkteik/Thailand	THLAND-S
OSE/Taiwan	TAIWAN-T
Unisem/Malaysia	MALAY-U
VLSI/USA	USA-V
Toshiba/USA	USA-W
Cypress Bangkok/Thailand	ALPHA-X
Alphatech/Thailand	ALPHA-Y

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## Description of Data Table Column Headings

Column Heading	Description of Column Contents
Prod Line	Product Line or Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Temp/humidity/bias conditions for the stress. See table on previous page for detail.
Device ID	Cypress manufacturing part number for specific type.
Date Code	Week in which the specific lot was sealed/molded.
Lot Number	Manufacturing (assembly) lot number of material stressed.
Function	Generic product family at Cypress.
Description	Brief description of device function.
Technology	Fabrication process technology. See Cypress Product Matrix for detail.
Process	Generic fabrication process.
Process Location	State where fabrication facility is located. See table on previous page for detail.
Pkg Material	Generic packaging material
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Package Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin count of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC)=Cycles; all other stresses=Hours.
# Tested	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.





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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func- tion	Description	Technology	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
LOGIC	HAST	130C/5.5V	CY7C9101-40JC	95052	9516	12957 (SWR)	LOGIC	16-BITS SLI	SRAM/LOGIC-L13	CMOS	TX	PLCC	PHIL-M	68	128	45	0	
		140C/5.5V	CY7C136-55JC	95152	9525	349511311	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	128	48	0	
				95487	9547	349524032	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	128	48	0	
			CY7C4245-30JC	95243	9531	349515555	FIFO	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	68	128	50	0	
			CY7C9101-40JC	95052	9516	12957 (SWR)	LOGIC	16-BITS SLI	SRAM/LOGIC-L13	CMOS	TX	PLCC	PHIL-M	68	128	45	0	
			VIC068A-BC	95026	9433	49408036	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA	USA-V	144	128	40	0	
					9502	349414269B	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA	USA-V	144	128	45	0	
	HTOL	150C/5.5V	CY7C136-55LMB	95152	9527	219509592	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	LCC	ALPHA-X	52	184	50	0	
		150C/5.75V	CY7B145-25JC	95052	9530	13123	SRAM	8K x 9 DP	BICMOS-SM2	BICMOS	TX	PLCC	PHIL-M	68	184 500	45 45	0 0	
			CY7C136-55JC	95152	9525	349511311	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	48 80 500	10 126 126	0 0 0	
				95487	9547	349524030	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	48	504	0	
						349524032	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	48	504	0	
			CY7C136-55LM	95152	9530	219510650	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	LCC	ALPHA-X	52	48 80 500	510 120 120	0 0 0	
			CY7C146-55JC	95152	9535	349518104	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	48	504	0	
			CY7C4245-30JC	95243	9531	349515555	FIFO	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	68	48 80 500 1000 2000	758 126 126 116 116	0 0 0 0 0	
	HTS	165C/NO BIAS	CY7C9101-40JC	95052	9516	12957 (SWR)	LOGIC	16-BITS SLI	SRAM/LOGIC-L13	CMOS	TX	PLCC	PHIL-M	68	336	45	0	
	HTSSL	150C/5.75V	CY7B145-25JC	95052	9530	13123	SRAM	8K x 9 DP	BICMOS-SM2	BICMOS	TX	PLCC	PHIL-M	68	80 168	76 76	0 1	NON-VISUAL
			CY7C136-55JC	95152	9525	349511311	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC	KOREA-A	52	80 168	80 80	0 0	
			CY7C136-55LM	95152	9530	219510650	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	LCC	ALPHA-X	52	168	84	0	
	HTSSL2	125C/7.0V	CY7C4245-30JC	95243	9531	349515555	FIFO	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	68	168	76	0	

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func- tion	Description	Technology	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
LOGIC	HTSSL2	125C/7.0V	CY7C4245-30JC	95243	9531	349515555	FIFO	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	68	336 500	76 76	0 0	



PCT	121C/100%RH	CY7C136-55JC	95152	9525	349511311	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	168	48	0
			95487	9547	349524032	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	168	48	0
		CY7C4245-30JC	95243	9531	349515555	FIFO	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	PLCC KOREA-A	68	168	52	0
		CY7C9101-40JC	95052	9516	12957 (SWR)	LOGIC	16-BITS SLI	SRAM/LOGIC-L13	CMOS	TX	PLCC PHIL-M	68	168	45	0
		VIC068A-BC	95026	9433	49408036	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA USA-V	144	168	45	0
T/S	-55C TO 150C			9502	349414269B	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA USA-V	144	168	45	0
		CY7C9101-40JC	95052	9516	12957 (SWR)	LOGIC	16-BITS SLI	SRAM/LOGIC-L13	CMOS	TX	PLCC PHIL-M	68	100	45	0
												200	45	0	0
		VIC068A-BC	95026	9502	349414269B	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA USA-V	144	100	45	0
												200	45	0	0
TC	-40C TO 125C	CY7C9101-40JC	95052	9516	12957 (SWR)	LOGIC	16-BITS SLI	SRAM/LOGIC-L13	CMOS	TX	PLCC PHIL-M	68	500	95	0
												1500	94	0	0
		VIC068A-BC	95026	9502	349414269A	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA USA-V	144	500	45	0
												1500	45	0	0
				9532	349512348	BUS	VME BUS	SRAM/LOGIC-C2AN	CMOS	MN	PPGA USA-V	144	500	50	0
TC2	-65C TO 150C											1500	50	0	0
		CY7C136-55JC	95152	9525	349511311	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	300	48	0
				9533	349516090	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	300	48	0
			95487	9547	349524030	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	300	48	0
					349524031	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	300	48	0
					349524032	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	PLCC KOREA-A	52	300	48	0
		CY7C136-55LM	95152	9530	219510650	SRAM	2K x 8 DP	SRAM/LOGIC-R21	CMOS	TX	LCC ALPHA-X	52	100	50	0
												1000	50	0	0
		CY7C4245-30JC	95243	9531	349515555	FIFO	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	PLCC KOREA-A	68	300	50	0
TEV	0 READ POINT	CY7B145-25JC	M53035	9538	349519727	SRAM	8K x 9 DP	BICMOS-SM2	BICMOS	TX	PLCC KOREA-A	68	-5	120	0
													25	120	0
													85	120	0

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
MTI	HTOL	150C/5.75V	CYM1830HD	95346	9534	507329	SRAM	64Kx32	SMT	MIL	SJ	DIP	APLUS	NA	184	16	0	
	TC	-0C TO 125C	CYM1841CPZ	95461	9543	9543143	SRAM	256Kx4	SMT	STD	SJ	ZIP	AMT	NA	100	16	0	
			CYM74A430PM	95442	9534	508061	SRAM	256K TCACHE	SMT	STD	SJ	SIMM	AMT	NA	100	16	0	
			CYM74B430PM	95443	9504	508126	SRAM	256K TCACHE	SMT	STD	SJ	SIMM	HANA	NA	100	16	0	



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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func- tion	Description	Technology	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
PLD	DRET	165C/NO BIAS	CY7C371-100JC	M52041	9523	349510044	PLD	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	44	168 1000	45 45	0 0	
			PALC22V10D-10JC	95425	9536	3495158508	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	168 552	78 78	0 0	
					9538	349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	168 552	78 78	0 0	
			PALC22V10D-10PC	95425	9539	591500237	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PDIP	INDNS-O	24	168 552	78 78	0 0	
			PALCE20V8-25JC	95173	9531	349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	168 552	78 78	0 0	
			PALCE20V8-25PC	95173	9528	349514098	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PDIP	INDNS-O	24	168 552	80 80	0 0	
	HAST	130C/5.5V	CY7C375-100AC	95223	9421	49405621	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-A	160	50 128	24 24	0 0	
			CY7C388A-2NC	94521	9521	1509257	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	50 128	4 4	0 0	
					9523	1513339 349509393	FPGA FPGA	8K GATE 8K GATE	FAMOS-VL26D FAMOS-VL26D	CMOS CMOS	CA CA	PQFP PQFP	KOREA-A KOREA-A	208 208	256 50	14 34	0 0	
															128 256	78 64	0 0	
					9529	349509804	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	50 128	14 14	0 0	
					9536	1508232	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	128 256	11 11	0 0	
		140C/5.5V	CY7C344-25PC	M52035	9517	349506849	PLD	REPROG. PAL	FAMOS-P20DHL	CMOS	TX	PDIP	INDNS-O	28	128	80	0	
			CY7C371-100JC	M52039	9523	349510044	PLD	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	44	128	16	1	1 TOPSIDE CRACKS
			CY7C374-100JC	95222	9523	349510045	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	84	128	47	0	
			CY7C375-100AC	95223	9443	349412808	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-Q	160	64 128 192 256	48 48 48 48	0 0 0 0	
			CY7C387A-2AC	95348	9531	349512442	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	TQFP	KOREA-Q	144	128	45	0	
			PALC22V10-40JC	95052	9516	12956 (SWR)	PLD	S/PLD24	FAMOS-P13	CMOS	TX	PLCC	PHIL-M	28	128	45	0	
			PALC22V10D-10JC	95425	9536	3495158508	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	128	48	0	
					9538	349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	128 256	46 46	0 0	

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func- tion	Description	Technology	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
PLD	HAST	140C/5.5V	PALCE20V8-25JC	95173	9531	349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	128	51	0	1 EOS



CYPRESS  
SEMICONDUCTOR  
PRODUCT RELIABILITY

HTOL	150C/5.50V	PALCE20V8-25PC	95173	9528	349514098	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PDIP	INDNS-O	24	128	47	0		
		CY7C387A-2NC	94521	9527	1452956	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	48	9	0		
		CY7C388A-2NC	94521	9521	1509257	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	48	106	0		
														168	106	0		
														500	76	0		
				9527	1452956	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	168	42	0	2	EOS
														500	42	0		
					1507188	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	48	15	0		
														168	15	0		
														500	15	0		
				9528	1452956	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	48	6	0		
														168	6	0		
	150C/5.75V			1509257	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	48	46	0	1	EOS	
														168	47	0		
				9529	1515408	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	48	80	0		
														168	80	0		
														500	80	0		
		CY7C374-100GC	95222	9521	219507329	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	CPGA	ALPHA-X	84	80	79	0		
														500	79	0		
		CY7C374-100GMB	95222	9522	219507690	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	CPGA	ALPHA-X	84	184	45	0		
		CY7C375-100GMB	95411	9534	219511847	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	CPGA	ALPHA-X	160	80	79	0		
														500	79	0		
		PALC22V10-40JC	95052	9516	12955(SWR)	PLD	S/PLD24	FAMOS-P13	CMOS	TX	PLCC	PHIL-M	28	168	45	0		
					12956(SWR)	PLD	S/PLD24	FAMOS-P13	CMOS	TX	PLCC	PHIL-M	28	500	45	0		
												184	45	0				
		PALC22V10D-10JC	95425	9536	3495158508	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	48	1244	0		
														80	117	0		
														500	117	0		
				9538	349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	48	505	0		
														80	117	0		
														500	117	0		
														1000	117	0		
		PALC22V10D-10PC	95425	9539	591500237	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PDIP	INDNS-O	24	48	513	0		
														80	139	0		
														500	139	0		
				9542	519501118	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PDIP	INDNS-O	24	48	340	0		
		PALCE20V8-25JC	95173	9531	349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	48	507	0		

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
PLD	HTOL	150C/5.75V	PALCE20V8-25JC	95173	9531	349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	80	117	0	
															500	234	0	
			PALCE20V8-25PC	95173	9528	349514098	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PDIP	INDNS-O	24	48	527	0	
															80	131	0	
															500	131	0	
HTOL2	125C/5.75V		CY7C342-40JC	M52017	9521	349509096	PLD	REPROG.PAL	FAMOS-P20DHL	CMOS	TX	PLCC	KOREA-A	68	96	119	0	
															500	119	0	
															1000	119	0	
															2000	119	0	
HTS	165C/NO BIAS		CY7C375-100AC	95223	9424	49406783	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-A	160	336	18	0	



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**CYPRESS  
SEMICONDUCTOR  
PRODUCT RELIABILITY**

						9510	1452955	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	168	30	0
						9515	1452956	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	168	30	0
						95052	12955 (SWR)	PLD	S/PLD24	FAMOS-P13	CMOS	TX	PLCC	PHIL-M	28	168	45	0
							12956 (SWR)	PLD	S/PLD24	FAMOS-P13	CMOS	TX	PLCC	PHIL-M	28	168	45	0
						95425	3495158508	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	168	50	0
							349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	168	50	0
						9538	349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	168	46	0
							349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	168	46	0
						95173	349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	168	52	0
							349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	168	52	0
						95173	349514098	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PDIP	INDNS-O	24	168	49	0
							349514098	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PDIP	INDNS-O	24	168	49	0
T/S	-55C TO 150C	CY7C375-100AC	95223	9424	49406781/7	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-A	160	100	200	49	47	0
		CY7C388A-2NC	94521	9521	1509257	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	100	200	45	45	0
TC	-40C TO 125C	CY7C375-100AC	95223	9421	49405621	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-A	160	500	1000	49	49	0

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
PLD	TC	-40C TO 125C	CY7C375-100AC	95223	9443	349412808	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-Q	160	500	49	0	
															1000	49	0	
															1500	49	0	
TC2	-65C TO 150C	CY7C342-40HC	M52027	9515	349507933	PLD	REPROG. PAL	FAMOS-P20DHL	CMOS	TX	WHLC	PHIL-M	68	300	1000	49	49	0
		CY7C344-25PC	M52036	9517	349506849	PLD	REPROG. PAL	FAMOS-P20DHL	CMOS	TX	PDIP	INDNS-O	28	300	1000	50	0	
		CY7C374-100GC	95222	9521	219507329	PLD	128 MCEL FL	FLASH-FL22D	CMOS	CA	CPGA	ALPHA-X	84	100	1000	48	0	
		CY7C387A-2AC	95348	9529	349514788	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	TQFP	KOREA-Q	144	300		45	0	
		CY7C388A-2NC	94521	9503	1445679	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	300	1000	45	45	0
					9510	1452955	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	300		30	0
					9515	1452956	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	300		15	0
					9529	1515408	FPGA	8K GATE	FAMOS-VL26D	CMOS	CA	PQFP	KOREA-A	208	300	1000	45	0
		PALC22V10D-10JC	95425	9536	3495158508	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	300	500	48	46	0
				9538	349520602B	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PLCC	KOREA-A	28	300	1000	46	0	
																46	0	
		PALC22V10D-10PC	95425	9539	591500237	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PDIP	INDNS-O	24	300	1000	48	0	
					519501118	PLD	S/PLD24	FLASH-FL24D	CMOS	TX	PDIP	INDNS-O	24	300	1000	48	48	0
		PALCE20V8-25JC	95173	9531	349515484	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	28	300		51	0	



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		PALCE20V8-25PC	95173	9528	349514098	PLD	S/PLD24	FLASH-FL22D	CMOS	CA	PDIP	INDNS-O	24	300 1000	48 48	0 0
TEV	0 READ POINT	CY7C371-100JC	M53009	9535	349518118	PLD	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	44	-5 25 85	80 80 80	0 0 0

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SRAM	HAST	140C/5.5V	CY7C109A-35VC	M52024	9528	349512520	SRAM	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	128	68	0	
			CY7C1399-35VC	95417	9531	219511102	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	128	45	0	
					9541	219515206	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	128	45	0	
			CY7C185-35VC	95311	9532	219511700	SRAM	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	128	54	0	
			CY7C188-25VC	95462	9529	349514205	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	KOREA-L	32	128	46	0	
				9539	349521492	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	KOREA-L	32	128	24	0		
			CY7C199-15PC	M53022	9541	219515020	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	PDIP	ALPHA-X	28	128	80	0	
			CY7C199-15VC	95201	9520	13026 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	128	50	0	
						13027 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	128	48	1	1 POLY DEFECT
						13028 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	128	48	1	1 PARTICLE
				95252	9517	349507034	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	128	48	0	
						349507035	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	128	48	0	
						349507036	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	128	48	0	
				95364	9530	219510849	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	128	48	0	
						219510850	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	128	50	0	
						219510852	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	128	50	0	
				95365	9537	3532176	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	128	48	0	
					9539	349521304	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	128	46	0	
				M53004	9527	219509711	SRAM	256K/R3	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	128	78	1	1 PARTICLE
				M53016	9536	349519413	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	128	80	0	
				M53040	9529	349514101	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	128	80	0	
	CY7C199-45VI	M53033	9538	349520839	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	128	80	0			
HTOL	150C/5.75V	CY7C109A-35VC	95384	9532	349515472	SRAM	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	48	1096	0		
				9534	349517503	SRAM	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	48	1107	0		
				9538	349513240	SRAM	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	48	1095	0		
		CY7C185-35VC	95311	9532	219511700	SRAM	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	48	755	0		
													80	270	0			
												500	270	0				
		CY7C188-25VC	95462	9529	349514205	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	KOREA-L	32	48	10	0	2 EOS	



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48 759 0  
80 120 0  
500 134 0  
9539 349521492 SRAM 256K/R2 SRAM/LOGIC-R21 CMOS TX SOJ KOREA-L 32 48 749 0

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SRAM	HTOL	150C/5.75V	CY7C199-15PC	95252		3447347	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	PDIP	KOREA-A	28	48 80 500	565 120 120	0 0 0	
				95364	9533	219511651	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	PDIP	ALPHA-X	28	48 80 390	897 118 118	0 0 0	
			CY7C199-15VC	95364	9530	219510848	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	80 500 668	120 120 120	0 0 0	
						219510849	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	48 500	766 10	0 0	
						219510850	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	48 80 500	756 120 120	0 0 0	
						219510851	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	80 500 620	120 120 108	0 0 0	1 BPSG DEFECT
						219510852	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	48 80 500 668	750 120 120 120	1 0 0 0	1 PHOTORESIST DEFECT
				95365	9537	3532176	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	48 80 500	510 121 131	0 0 0	
				9539	349521304	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	48 80 500	756 118 118	0 0 0		
				9541	349521870	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	48 80 500	528 118 118	0 0 0		
HTOL2	125C/4.80V		CY7C1399-35PC	95417	9533	219511913	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	PDIP	ALPHA-X	28	48 80 500 650 1000	745 116 114 113 113	0 0 1 0 0	5 EOS 2 EOS/1 POLY DEFECT
			CY7C1399-35VC	95417	9531	219511101	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	168 500	10 10	0 0	
				9541	219515123	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	48 80 500	707 115 114	1 0 0	1 POLY DEFECT 1 EOS	
						219515206	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	48 80 394	741 116 112	0 0 0	1 EOS

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Duration	Qty Test	Qty Fail	Fail Mode
SRAM	HTOL2	125C/4.80V	CY7C1399-35VC	95417	9541	219515206	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	500	112	0	
					9543	219515582	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	48	1034	0	
															80	116	0	
															500	116	0	
		125C/5.75V	CY7C109A-35VC	M52004	9522	349509018	SRAM	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	96	120	0	
															500	120	0	
															1000	120	0	
															2000	120	0	
			CY7C199-45VI	M52012	9521	219507380	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	ALPHA-X	28	96	127	0	
															500	127	0	
															1000	123	0	
															2000	123	0	
HTS	165C/NO BIAS	CY7C199-15VC	95201	9520	13026 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	336	54	0		
														500	54	0		
														1000	54	0		
					13027 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	336	54	0		
														500	54	0		
														1000	54	0		
				95252	9517	349507034	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	336	54	0	
															500	53	0	
						349507035	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	336	54	0	
															500	54	0	
															1000	54	0	
				95364	9530	219510850	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	336	54	0	
															500	54	0	
															1000	54	0	
HTSSL	150C/4.0V	CY7C1399-35PC	95417	9533	219511913	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	PDIP	ALPHA-X	28	80	74	0	2 EOS	
														168	74	0		
		CY7C1399-35VC	95417	9543	219515582	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	80	76	0		
														168	76	0		
		150C/5.75V	CY7C185-35VC	95311	9532	219511700	SRAM	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	80	81	0	
															168	81	0	
CY7C188-25VC	95462	9529	349514205	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	KOREA-L	32	80	80	0				
												168	80	0				
CY7C199-15PC	95364	9533	219511651	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	PDIP	ALPHA-X	28	80	77	0				
												168	77	0				
CY7C199-15VC	95364	9530	219510850	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	80	81	0				
												168	81	0				

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SRAM	HTSSL	150C/5.75V	CY7C199-15VC	95364	9530	219510852	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	80	81	0	
															168	81	0	
				95365	9537	3532176	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	80	81	0	
															168	81	0	
				9539	349521304		SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	80	78	0	
															168	78	0	



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HTSSL2	125C/4.0V	CY7C1399-35VC	95417	9541	219515206	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	80 168	76 76	0 0
	125C/4.80V	CY7C1399-35VC	95417	9541	219515123	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	80 168	76 76	0 0
LTOL	-45C/6.5V	CY7C199-15PC	95364	9518	349507986	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	PDIP	INDNS-O	28	500 1000	45 45	0 0
PCT	121C/100%RH	CY7C1399-35VC	95417	9531	219511102	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	168	45	0
				9541	219515206	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	168 288	45 45	0 0
		CY7C185-35VC	95311	9532	219511700	SRAM	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	168	52	0
		CY7C188-25VC	95462	9529	349514205	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	KOREA-L	32	168	46	0
		CY7C199-15VC	95201	9520	13026 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	168	54	0
					13027 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	168	54	0
			95252	9517	349507034	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	168	54	0
					349507035	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	168	54	0
			95364	9530	219510850	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	168	50	0
					219510852	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	TX	SOJ	ALPHA-Y	28	168	50	0
			95365	9537	3532176	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	168	49	0
					349521304	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	168	46	0
TC2	-65C TO 150C	CY7C1399-35VC	95417	9531	219511102	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	300 1000	45 45	0 0
				9541	219515206	SRAM	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	300 1000	45 45	0 0
		CY7C185-35VC	95311	9532	219511700	SRAM	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300 1000	54 54	0 0
		CY7C188-25VC	95462	9539	349521492	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	KOREA-L	32	300	96	0
		CY7C199-12PC	95271	9534	349518224	SRAM	256K/R25	SRAM/LOGIC-R25	CMOS	MN	PDIP	INDNS-O	28	300 1000	96 48	0 0

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SRAM	TC2	-65C TO 150C	CY7C199-15VC	95201	9520	13026 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	300	54	0				
																1000	54	0			
																2000	53	0			
																PHIL-M	28	300	54	0	
																1000	54	0			
						13027 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	300	54	0				
																2000	54	0			
																PHIL-M	28	300	54	0	
																1000	54	0			
						13028 (SWR)	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	300	54	0				
																1000	54	0			
																2000	53	0			
				95252	9517	349507034	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	300	108	0				
														1000	108	0					
														2000	54	0					
						349507035	SRAM	256K/R28	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	300	108	0				



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											1000	108	0		
											2000	54	0		
											300	108	0		
											1000	54	0		
											2000	53	0		
													0		
											1000	48	0		
													0		
											300	50	0		
											300	100	0		
											1000	100	0		
											300	50	0		
													0		
											300	48	0		
											300	46	0		
											1000	46	0		
													0		
											300	50	5	5	TOPSIDE CRACKS
													0		
											25	120	0		
											85	120	0		
													0		
											25	120	0		
											85	120	0		
													0		
											25	120	0		
											85	120	0		

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM	TEV	0 READ POINT	CY7C199-45VI	M53030	9538	349520839	SRAM	256K/R2	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	-5	120	0	
																25	120	0
																85	120	0